

Lecture 4 – Testability Measures

- Purpose, origins
- Analysis, measures and computation
- Summary

Purpose

- Need approximate measure of:
 - Difficulty of setting internal circuit lines to 0 or 1 by setting primary circuit inputs
 - Difficulty of observing internal circuit lines by observing primary outputs
- Uses:
 - Analysis of difficulty of testing internal circuit parts – redesign or add special test hardware
 - Guidance for algorithms computing test patterns – avoid using hard-to-control lines
 - Estimation of fault coverage
 - Estimation of test vector length

Origins

- Control theory
- Rutman 1972 -- First definition of controllability
- Goldstein 1979 -- SCOAP
 - First definition of observability
 - First elegant formulation
 - First efficient algorithm to compute controllability and observability
- Parker & McCluskey 1975
- Brglez 1984 -- COP
- Seth, Pan & Agrawal 1985

Testability Analysis

- Involves Circuit Topological analysis, but no test vectors and no search algorithm
 - Static analysis
- Linear computational complexity
 - Otherwise, is pointless – might as well use automatic test-pattern generation and calculate:
 - Exact fault coverage
 - Exact test vectors

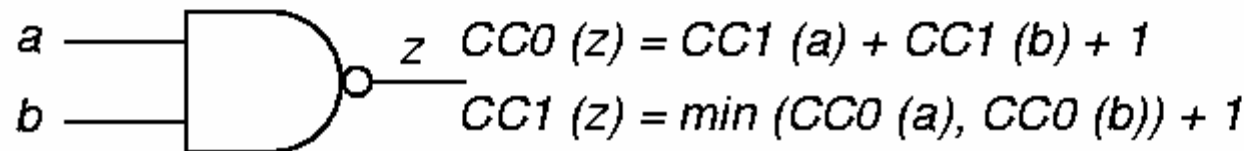
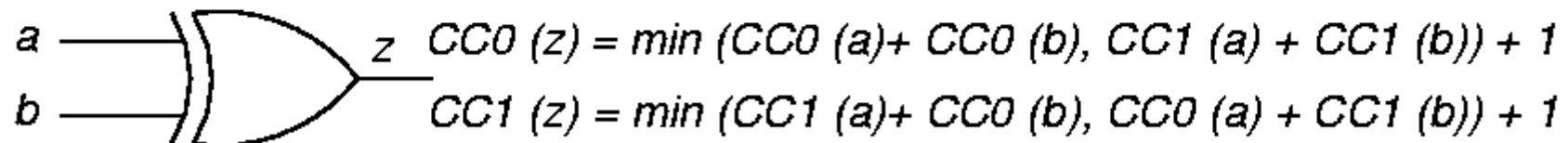
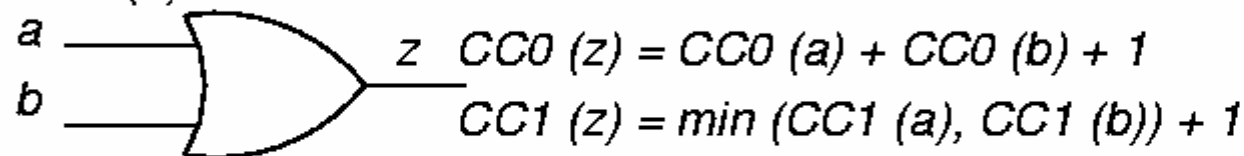
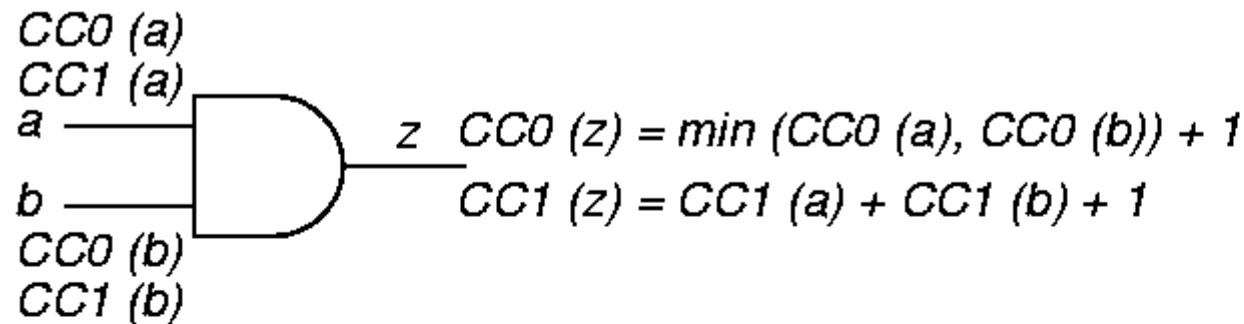
Types of Measures

- SCOAP – Sandia Controllability and Observability Analysis Program
- Combinational measures:
 - *CC0* – Difficulty of setting circuit line to logic 0
 - *CC1* – Difficulty of setting circuit line to logic 1
 - *CO* – Difficulty of observing a circuit line
- Sequential measures – analogous:
 - *SC0*
 - *SC1*
 - *SO*

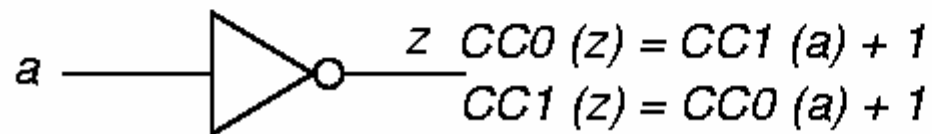
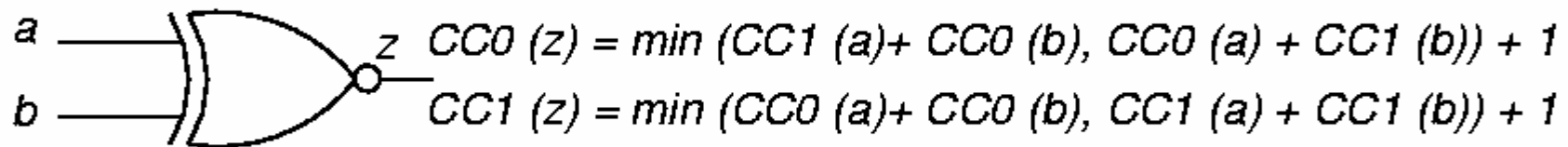
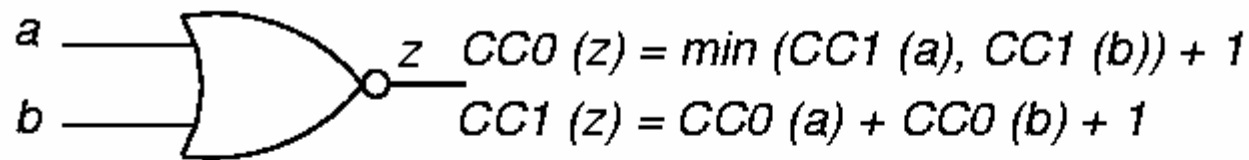
Range of SCOAP Measures

- Controllabilities – 1 (easiest) to infinity (hardest)
- Observabilities – 0 (easiest) to infinity (hardest)
- Combinational measures:
 - Roughly proportional to # circuit lines that must be set to control or observe given line
- Sequential measures:
 - Roughly proportional to # times a flip-flop must be clocked to control or observe given line

Controllability Examples

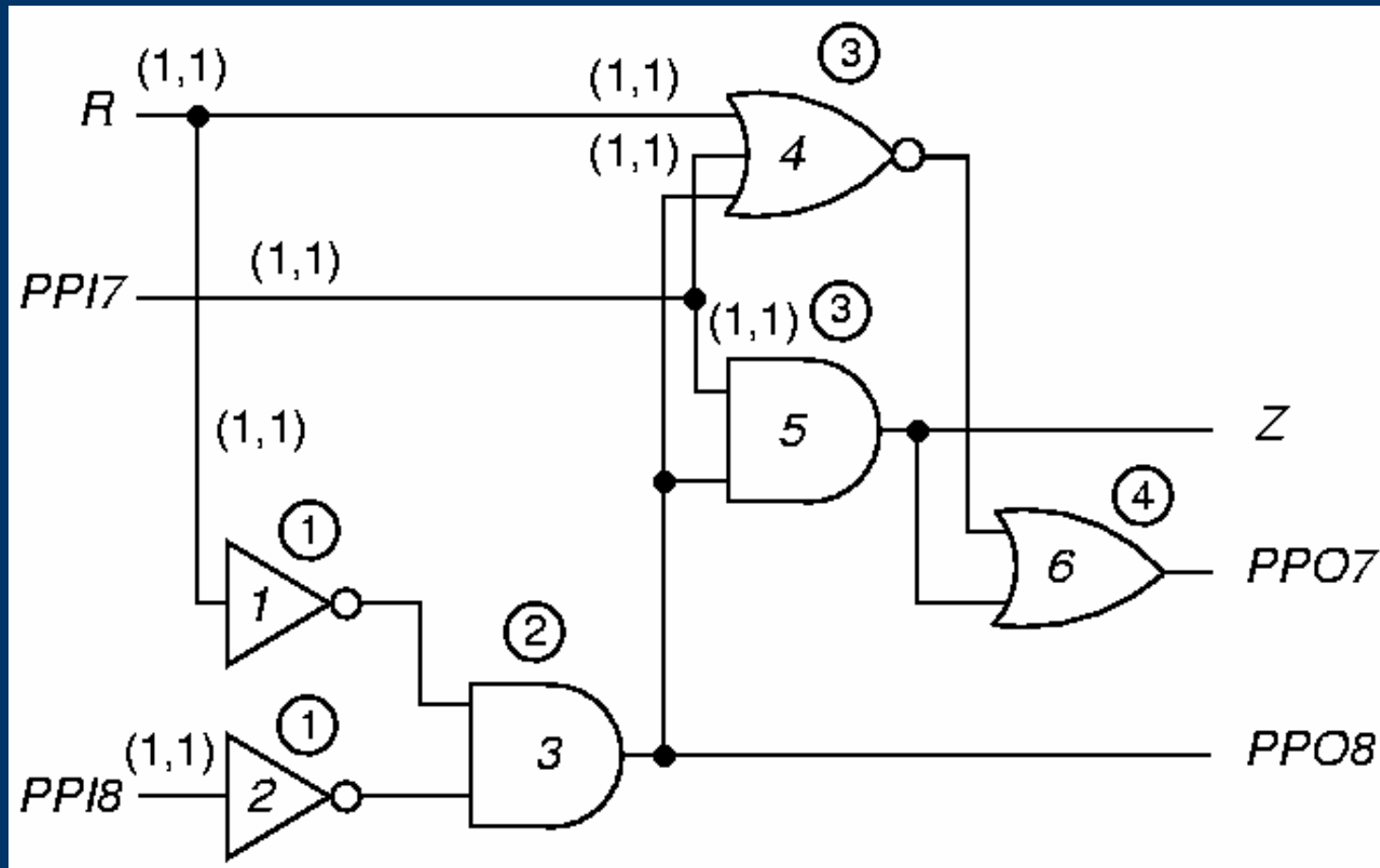


More Controllability Examples

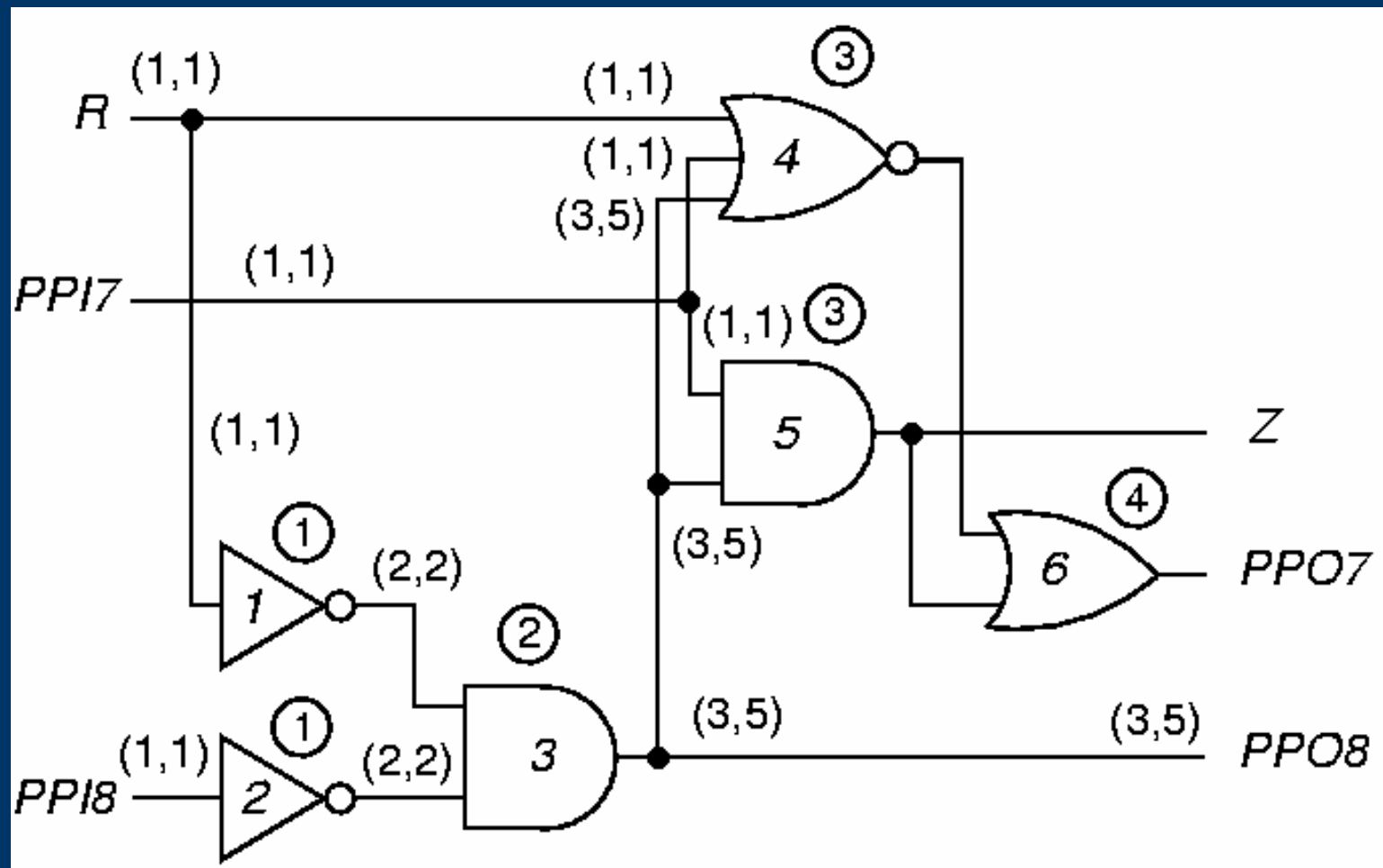


Controllability Through Level 0

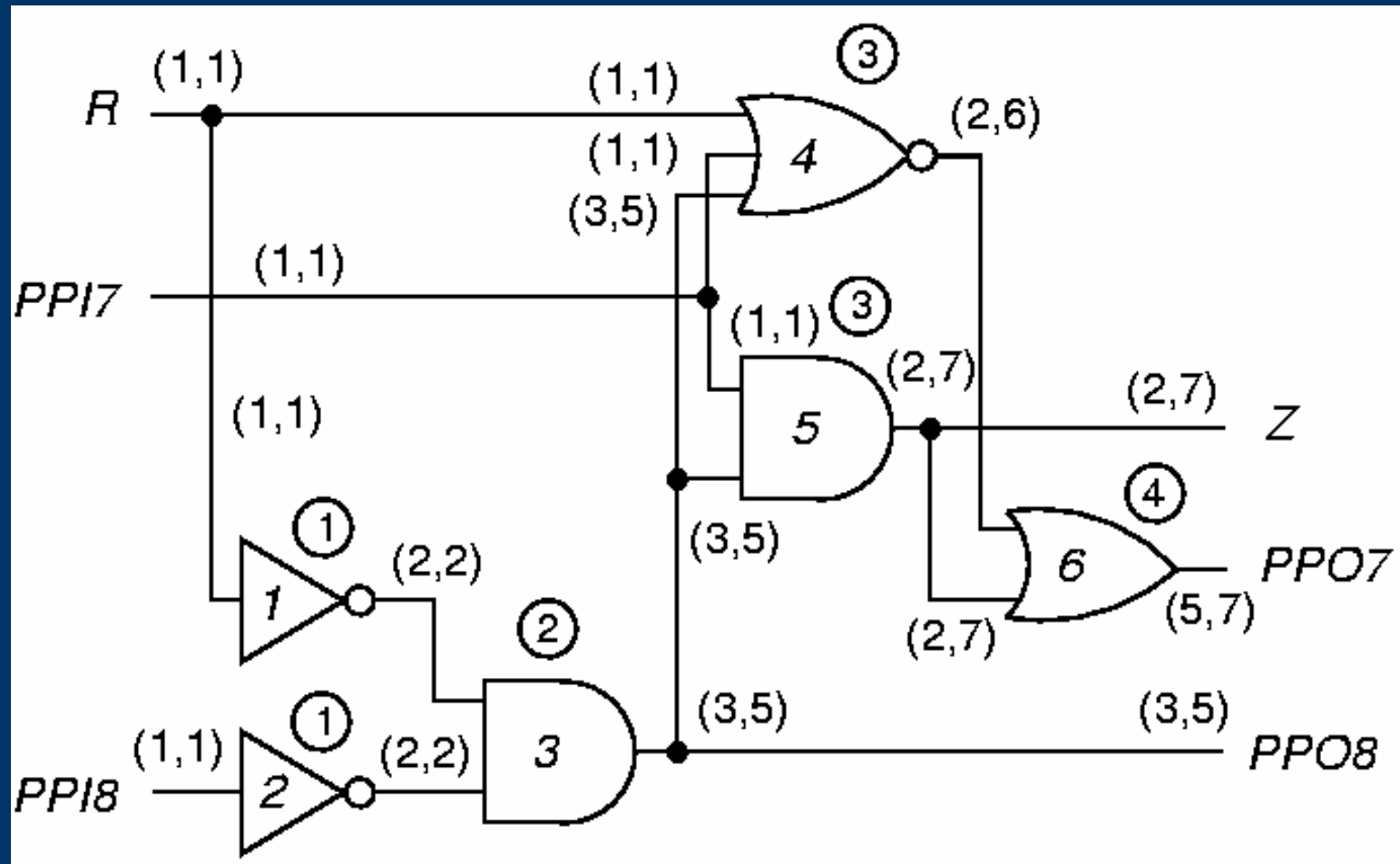
Circled numbers give level number. (CC0, CC1)



Controllability Through Level 2



Final Combinational Controllability



Observability Examples

To observe a gate input:

Observe output and make other input values non-controlling

$$CO(a) = CO(z) + CC1(b) + 1$$

$$CO(b) = CO(z) + CC1(a) + 1$$

$$CO(a) = CO(z) + CC0(b) + 1$$

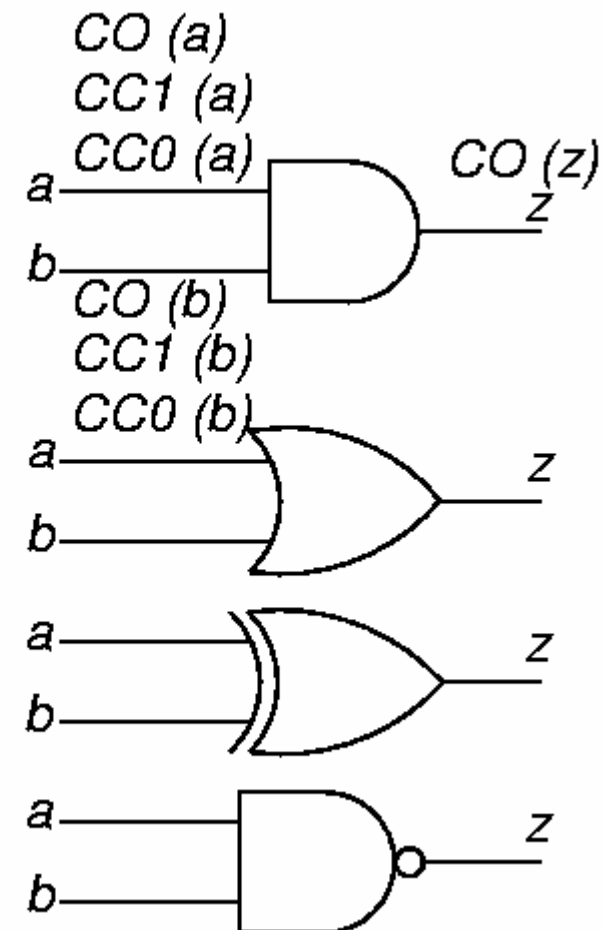
$$CO(b) = CO(z) + CC0(a) + 1$$

$$CO(a) = CO(z) + \min(CC0(b), CC1(b)) + 1$$

$$CO(b) = CO(z) + \min(CC0(a), CC1(a)) + 1$$

$$CO(a) = CO(z) + CC1(b) + 1$$

$$CO(b) = CO(z) + CC1(a) + 1$$



More Observability Examples

To observe a fanout stem:

Observe it through branch with best observability

$$CO(a) = CO(z) + CC0(b) + 1$$

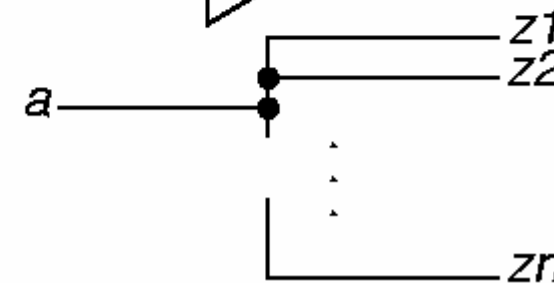
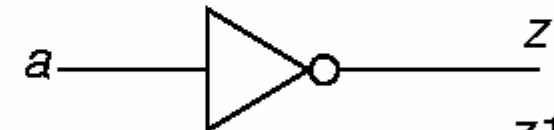
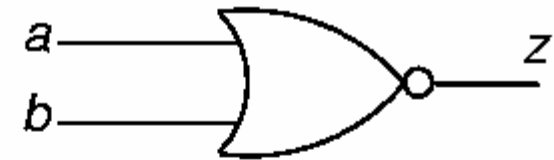
$$CO(b) = CO(z) + CC0(a) + 1$$

$$CO(a) = CO(z) + \min(CC0(b), CC1(b)) + 1$$

$$CO(b) = CO(z) + \min(CC0(a), CC1(a)) + 1$$

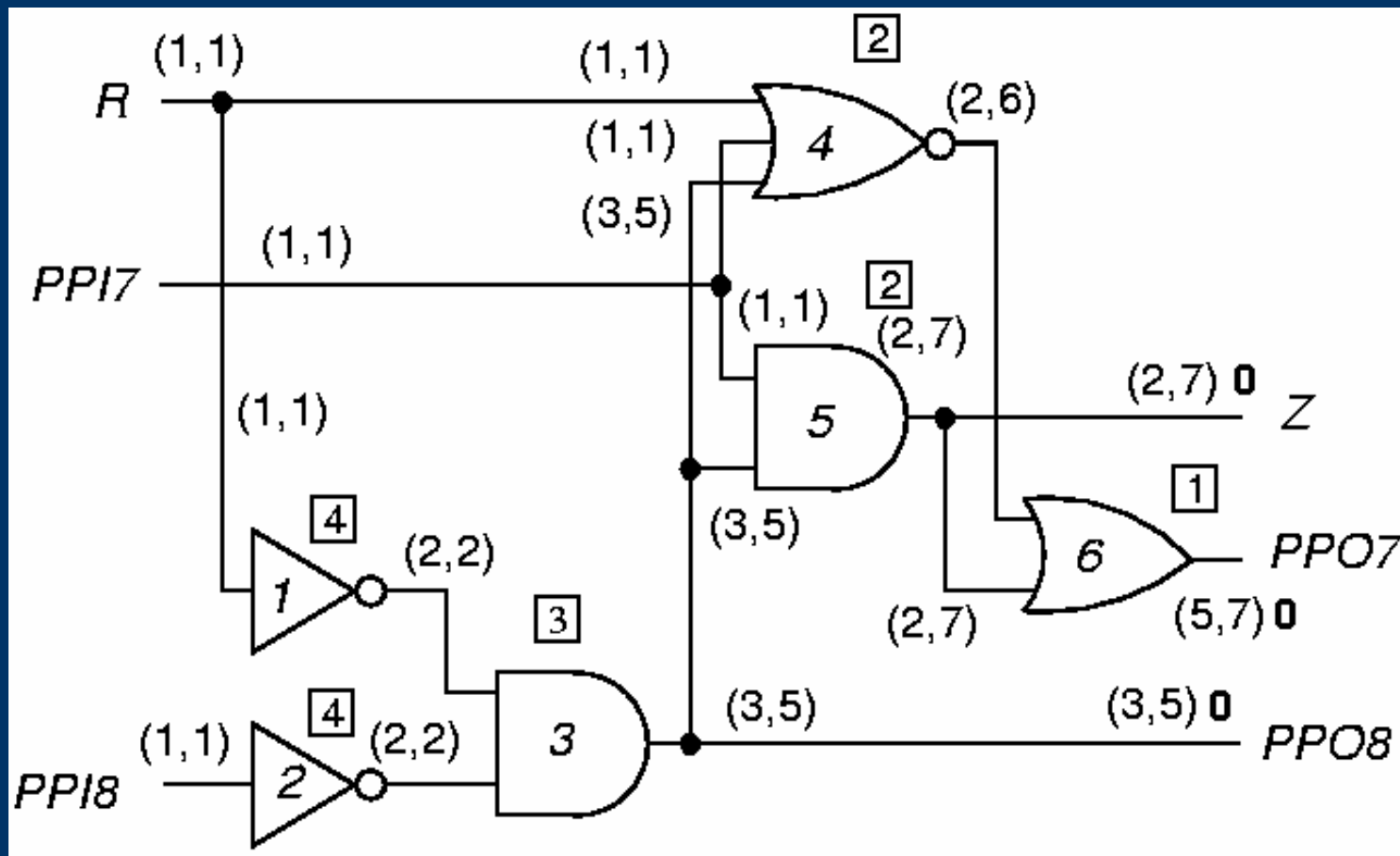
$$CO(a) = CO(z) + 1$$

$$CO(a) = \min(CO(z1), CO(z2), \dots, CO(zn))$$

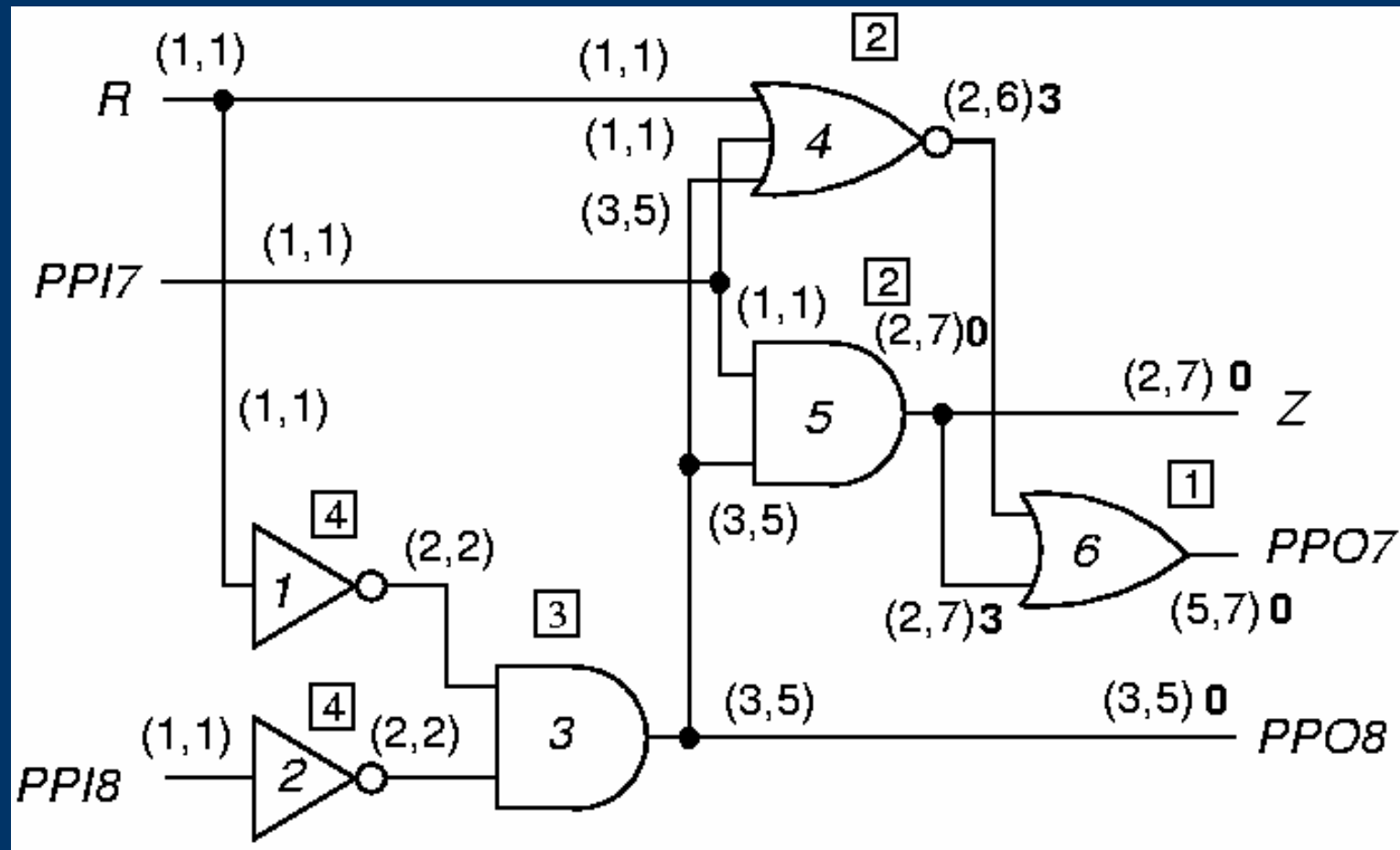


Combinational Observability for Level 1

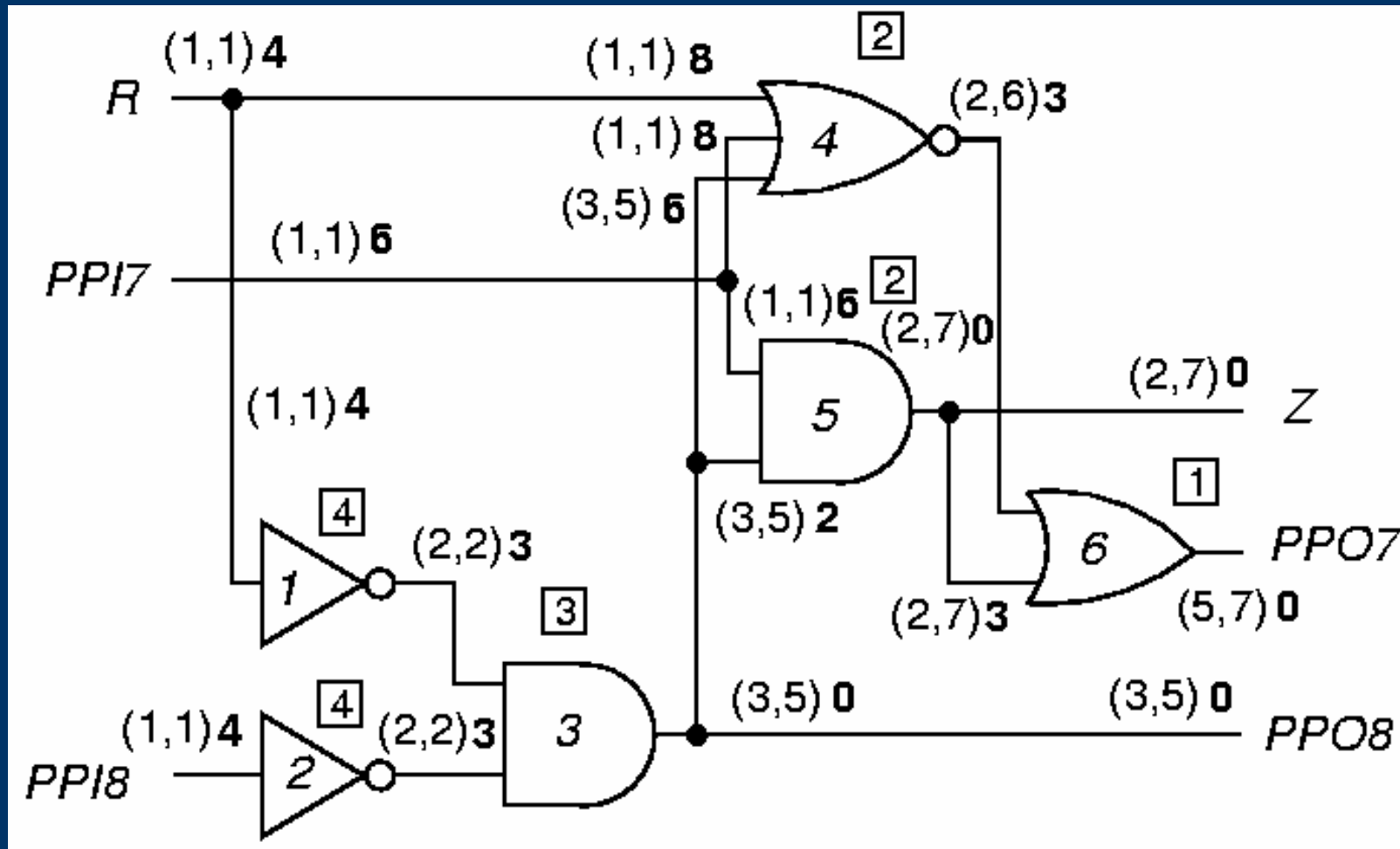
Number in square box is level from *primary outputs* (POs).
(CC0, CC1) CO



Combinational Observabilities for Level 2



Final Combinational Observabilities



Testability Computation

1. For all PIs, $CC0 = CC1 = 1$ and $SC0 = SC1 = 0$
2. For all other nodes, $CC0 = CC1 = SC0 = SC1 = \infty$
3. Go from PIs to POS, using CC and SC equations to get controllabilities -- Iterate on loops until SC stabilizes -- convergence guaranteed
4. For all POs, set $CO = SO = 0$
5. Work from POs to PIs, Use CO , SO , and controllabilities to get observabilities
6. Fanout stem $(CO, SO) = \min \text{branch } (CO, SO)$
7. If a CC or SC (CO or SO) is ∞ , that node is uncontrollable (unobservable)

Summary

- Testability approximately measures:
 - Difficulty of setting circuit lines to 0 or 1
 - Difficulty of observing internal circuit lines
- Uses:
 - Analysis of difficulty of testing internal circuit parts
 - Redesign circuit hardware or add special test hardware where measures show bad controllability or observability
 - Guidance for algorithms computing test patterns – avoid using hard-to-control lines
 - Estimation of fault coverage
 - Estimation of test vector length